IAP20 RESULTATION SO JAN 2006

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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant

Yamazaki et al.

Appl. No.

Unknown (U.S. National Phase of

PCT/JP2004/013633)

Filed

Herewith

For

POSITIVE RESIST

COMPOSITION AND METHOD

OF FORMING RESIST PATTERN

Examiner

Unassigned

Group Art Unit

Unknown

CERTIFICATE OF MAILING

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

January 30, 2006

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PRELIMINARY AMENDMENT

Mail Stop PCT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Prior to examination of the above-referenced application, please enter the following amendments.

Amendments to the Specification begin on page 2 of this paper.

Remarks begin on page 4 of this paper.